

General Description

The AOD404 uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and low gate resistance. This device is ideally suited for use as a high side switch in CPU core power conversion. Standard Product AOD404 is Pb-free (meets ROHS & Sony 259 specifications). AOD404L is a Green Product ordering option. AOD404 and AOD404L are electrically identical.

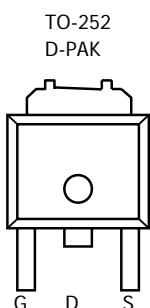
Features

V_{DS} (V) = 30V

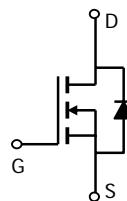
I_D = 85A (V_{GS} = 10V)

$R_{DS(ON)} < 7m\Omega$ (V_{GS} = 10V)

$R_{DS(ON)} < 8m\Omega$ (V_{GS} = 4.5V)



Top View
Drain Connected
to Tab



Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 12	V
Continuous Drain Current ^{B,G}	I_D	85	A
$T_C=25^\circ C$ ^G		65	
Pulsed Drain Current	I_{DM}	200	
Avalanche Current ^C	I_{AR}	30	A
Repetitive avalanche energy $L=0.1mH$ ^C	E_{AR}	120	mJ
Power Dissipation ^B	P_D	100	W
$T_C=100^\circ C$		50	
Power Dissipation ^A	P_{DSM}	2.5	W
$T_A=25^\circ C$		1.6	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 175	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	14.2	20	°C/W
Maximum Junction-to-Ambient Steady-State		39	50	°C/W
Maximum Junction-to-Case ^C	$R_{\theta JL}$	0.8	1.5	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=24\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		0.002	1	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 12\text{V}$			5	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1	1.6	2	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	85			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=20\text{A}$ $T_J=125^\circ\text{C}$		5.4	7	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=20\text{A}$		8.4	10.5	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=20\text{A}$		6.6	8	$\text{m}\Omega$
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.74	1	V
I_S	Maximum Body-Diode Continuous Current				85	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance			2100	2520	pF
C_{oss}	Output Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		536		pF
C_{rss}	Reverse Transfer Capacitance			165		pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		0.95	1.2	Ω
SWITCHING PARAMETERS						
$Q_g(4.5\text{V})$	Total Gate Charge			19.7	24	nC
Q_{gs}	Gate Source Charge	$V_{GS}=4.5\text{V}, V_{DS}=15\text{V}, I_D=20\text{A}$		3.6		nC
Q_{gd}	Gate Drain Charge			7.9		nC
$t_{D(\text{on})}$	Turn-On DelayTime			5.9	10	ns
t_r	Turn-On Rise Time	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=0.75\Omega,$		11	17	ns
$t_{D(\text{off})}$	Turn-Off DelayTime	$R_{\text{GEN}}=3\Omega$		36.2	55	ns
t_f	Turn-Off Fall Time			12	18	ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=20\text{A}, dI/dt=100\text{A}/\mu\text{s}$		35	42	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=20\text{A}, dI/dt=100\text{A}/\mu\text{s}$		33	50	nC

A: The value of R_{JJA} is measured with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The Power dissipation P_{DSM} is based on steady-state R_{JJA} and the maximum allowed junction temperature of 150°C. The value in any given application depends on the user's specific board design, and the maximum temperature of 175°C may be used if the PCB or heatsink allows it.

B: The power dissipation P_D is based on $T_{J(\text{MAX})}=175^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

C: Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=175^\circ\text{C}$.

D: The R_{JJA} is the sum of the thermal impedance from junction to case R_{JJC} and case to ambient.

E: The static characteristics in Figures 1 to 6 are obtained using <300 μs pulses, duty cycle 0.5% max.

F: These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The SOA curve provides a single pulse rating.

G: The maximum current rating is limited by the package current capability.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

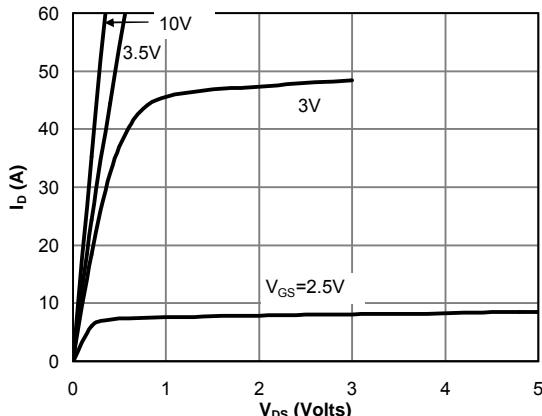


Fig 1: On-Region Characteristics

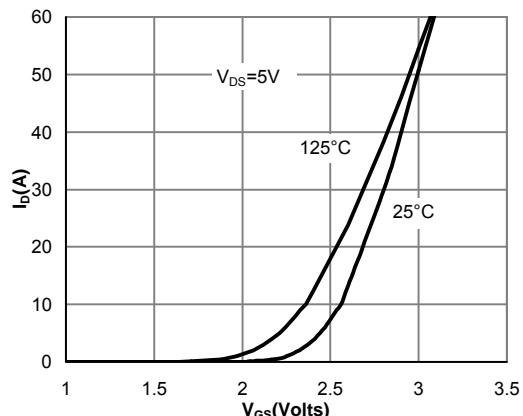


Figure 2: Transfer Characteristics

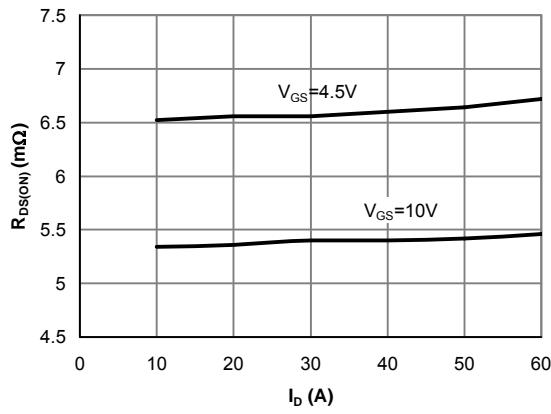


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

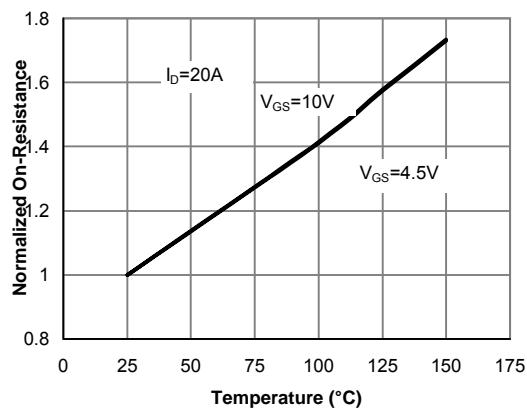


Figure 4: On-Resistance vs. Junction Temperature

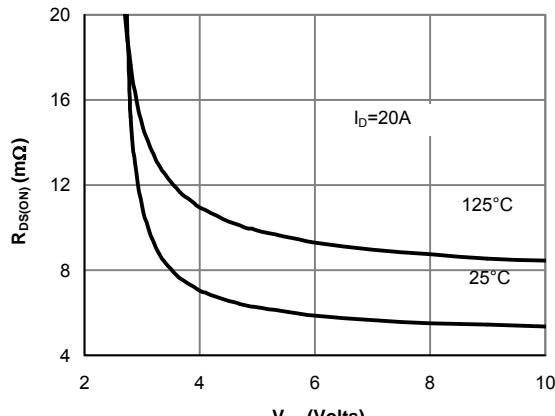


Figure 5: On-Resistance vs. Gate-Source Voltage

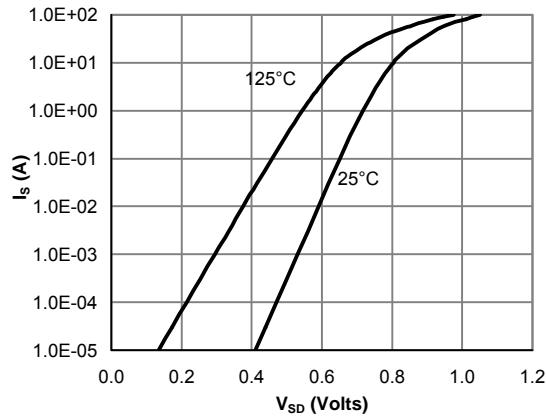
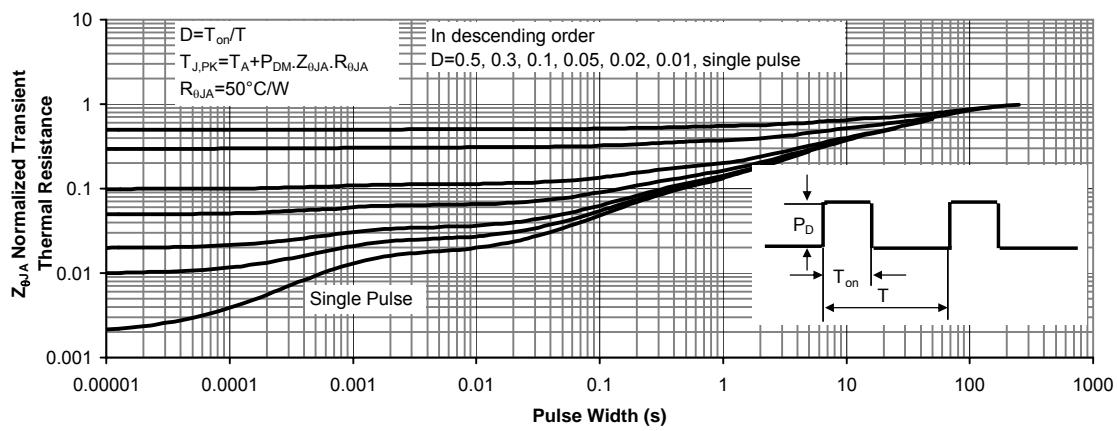
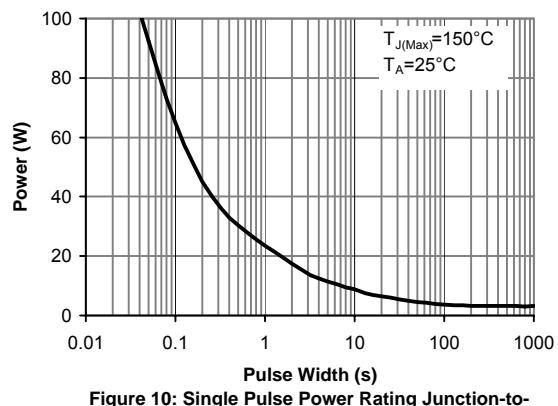
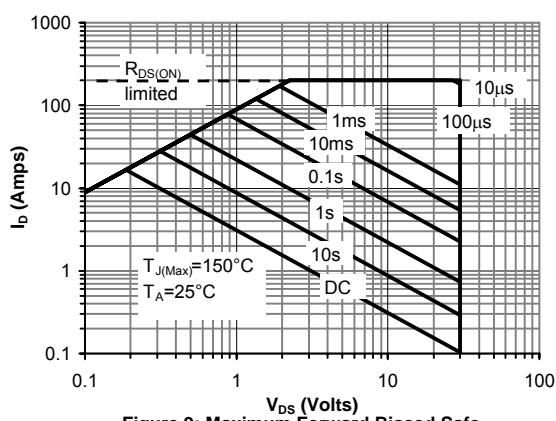
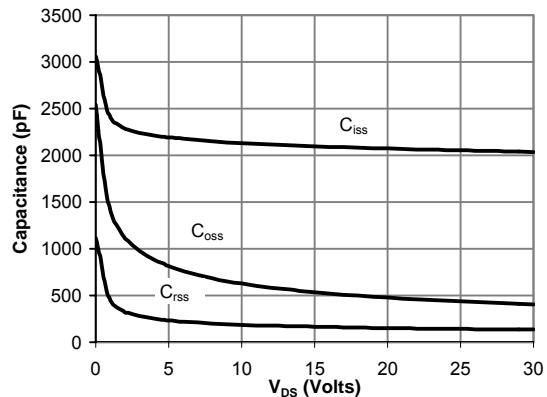
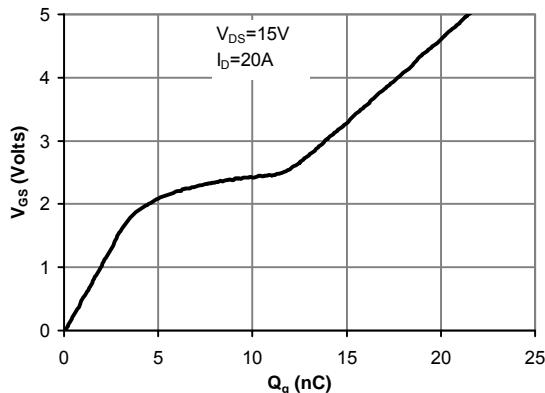


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



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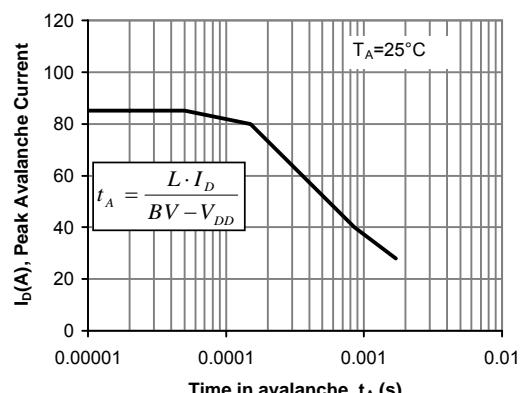


Figure 12: Single Pulse Avalanche capability

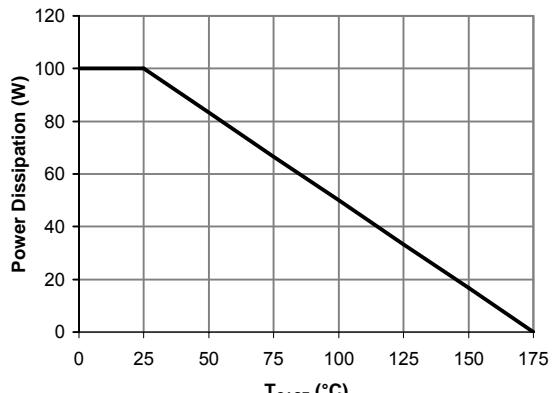


Figure 13: Power De-rating (Note B)

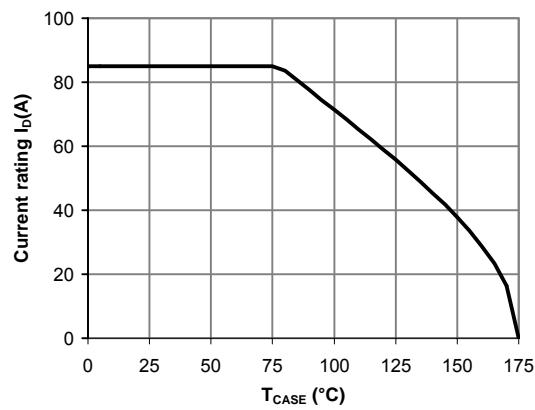


Figure 14: Current De-rating (Note B)